CHANGE NOTIFICATION



October 30 2012 PCN#: 103012

Dear Sir/Madam:

Subject: Notification of Assembly Process change for LTM8048

Please be advised that Linear Technology Corporation has made a minor change to the internal package construction to facilitate the use of one attach material for both die and components. The die attach material is changed from epoxy to solder, which is already used for attaching components in the same µModule package. In order to use the solder die attach, the die paddle (DAP) has been modified by splitting the DAP into multiple pads for dice D1, U1, and U2. Linear has been shipping several µModules using solder for die attach and component attach.

Besides these changes, no functional, parametric, mechanical, or datasheet specifications are affected and the component bill of materials remains unchanged. Similarly, there are no changes associated with the package footprint, PCB layout or product top marking, so customer applications will be unaffected.

Parts incorporating the new substrate design have been fully characterized and tested for package level reliability. The change was qualified by performing extensive characterization over the full operating voltage and temperature ranges, MSL3 preconditioning. Devices from the same μ Module product family have been subjected up to 1000 cycles of temperature cycles and thermal shock. Product built using the improved design is targeted for shipment around late November 2012.

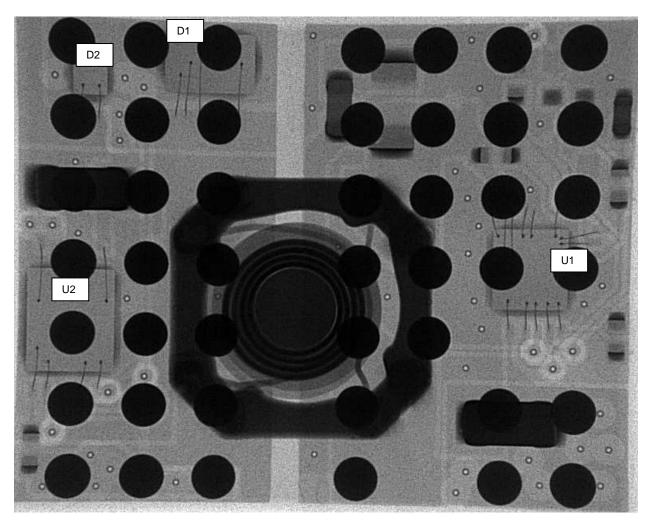
Should you have any further questions, please feel free to contact me at 408-432-1900 ext. 2519, or by E-mail at NGIRN@linear.com. If I do not hear from you by November 30, 2012, we will consider this change approved by your company.

Sincerely,

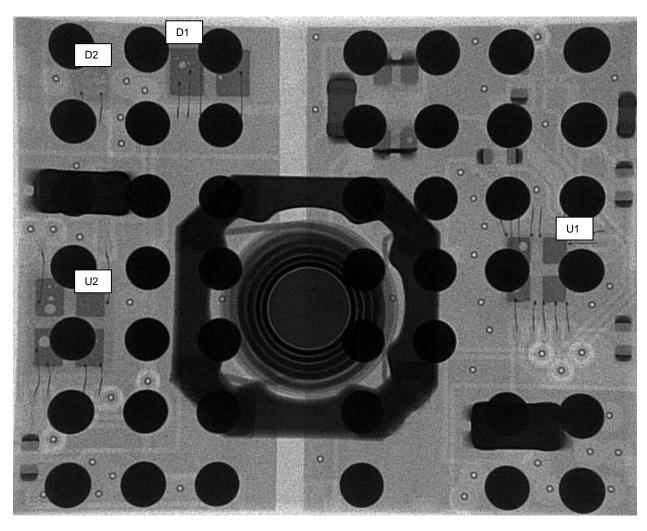
Naib Girn Quality Assurance Manager

Confidential Statement
This change notice is for Linear Technology's Customers only.
Distribution or notification to third parties is prohibited

LTM8048- CURRENT DESIGN (EPOXY DIE ATTACH) (No window pane on die attach pads)



LTM8048 - NEW DESIGN (SOLDER DIE ATTACH) (Window pane on die attach pads)





PACKAGE RELIABILITY DATA LTM80xx Solder Die Attach Qualification Report 10/23/2012

OPERATING LIFE TEST

• OPERATING LIFE TEST									
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +150°C	NUMBER OF FAILURES				
LTM8008	77 77	1210	1210	77.00 77.00	0 0				
• J-STD-020 MSL 3 PRECONDITIONING: 192h +30°C/60%R.H. SOAK, 3x REFLOW AT +245°C PEAK									
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		NUMBER OF FAILURES				
LTM8008 LTM8045 LTM8048	462 152 274 888	1210 1225 1232	1210 1225 1236		0 0 0				
• HIGH TEMPERATURE BAKE at 150°C									
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +150°C	NUMBER OF FAILURES				
LTM8008 LTM8045	77 50 127	1210 1225	1210 1225	77.00 50.00 127.00	0 0 0				
HIGHLY ACCELERATED STRESS TEST (+131°C/85%R.H. w BIAS)									
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +85°C	NUMBER OF FAILURES				
LTM8008	46 46	1210	1210	88.32 88.32	0 0				
• TEMPERATURE/HUMIDITY STORAGE (+85°C/85%R.H.) (1)									
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +85°C	NUMBER OF FAILURES				
LTM8008	77 77	1210	1210	77.00 77.00	0 0				



PACKAGE RELIABILITY DATA LTM80xx Solder Die Attach Qualification Report

10/23/2012 • TEMP CYCLE FROM -65°C to +150°C (1)								
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES			
LTM8008	231 231	1210	1210	231.00 231.00	0			
• TEMP CYCLE FROM -55°C to +125°C (1)								
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES			
LTM8045 LTM8048	77 25 102	1225 1232	1225 1232	38.50 12.50 51.00	0 0 0			
 THERMAL SHOC 	K FROM -65°C to +	150°C ⁽¹⁾						
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES			
LTM8008	231 231	1210	1210	231.00 231.00	0 0			
 THERMAL SHOC 	K FROM -55°C to +	125°C ⁽¹⁾						
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES			
LTM8045 LTM8048	75 49 124	1225 1232	1225 1232	75.00 24.50 99.50	0 0 0			
BOARD MOUNT	TEMP CYCLE FRO	M -40°C to +125°C						
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES			
LTM8008	15 15	1210	1210	22.50 22.50	0 0			
(1) Environmental	stress are preceded	by JEDEC Level 3 F	Preconditioning: 192	h 30°C/60% R.H. soak	, followed by 3x			

Reflow at 245°C

Page 2 of 2 Form: 00-03-6209B Rev. 1